

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HATHERILL ET AL.	
		Examiner Jason M. Han	Art Unit 2875	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,782,553	07-1998	McDermott, Kevin	362/245
*	B	US-2005/0018435	01-2005	Selkee et al.	362/427
*	C	US-2002/0030994	03-2002	Krietzman et al.	362/259
*	D	US-2004/0141316	07-2004	Twardawski, Harald	362/184
*	E	US-2004/0155844	08-2004	Stopa, James L.	345/082
*	F	US-6,140,776	10-2000	Rachwal, Erwin J.	315/200R
*	G	US-5,213,412	05-1993	Ciallella, Bruce	362/398
*	H	US-2002/0006039	01-2002	Ueda et al.	362/217
*	I	US-4,342,953	08-1982	Collins, John J.	320/136
*	J	US-6,109,766	08-2000	Baliozian, Mardick	362/287
*	K	US-6,357,893	03-2002	Belliveau, Richard S.	362/285
*	L	US-6,585,395	07-2003	Luk, John F.	362/250
*	M	US-2004/0223342	11-2004	Klipstein et al.	362/555

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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